

Hollow Cantilevers with Holes

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Hollow AFM Cantilever with Holes

Since its invention, atomic force microscopy (AFM) has enhanced our understanding of physical and biological systems at sub-micrometer scales. As the performance of AFM depends greatly on the properties of the cantilevers, many works have been done to improving cantilevers by means of modifying their geometries via lithography [1] and ion-beam milling [2,3] that primarily involved opening areas on the cantilever's face, resulting in high resonant frequency, low spring constant, and low hydrodynamic damping. Similar improvements were achieved using a hollow beam cantilever with nanoscale wall thickness [4]. In fact, the combination of these two approaches (in-plane opening and hollow beam) can result in unique metamaterial structures with tunable properties [5], but it has not been explored for AFM application.

In this work, we explore the hollow AFM cantilevers with in-plane modifications. We accomplished this by (1) taking a commercial solid silicon cantilever, (2) making a different number of holes on the face using pulsed laser micromachining, and (3) coating them with alumina using atomic layer deposition and etching the internal silicon that results in a hollow probe with holes. We present the effects of these modifications on the cantilever's resonant frequency, quality factor, and spring constant in air. This work provides an insight into strategies for tuning cantilever's properties for both flexural and torsional modes.

Keywords: Atomic force microscopy (AFM); flexural resonance; torsional resonance; hollow cantilever

Reference:

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Atomic Force Microscopy (AFM)

AFM Mechanism

AFM Operation





Dufrêne et al., Nature Nanotech. (12) 2017

- Measures forces between probe tip and sample surface
- Optical lever system measures deflection of cantilever

- Cantilever tip in direct contact with sample
- Sample and/or tip has high risk to be damaged

Contact Mode

- Cantilever vibrates at or near resonant frequency
- Tip interact with sample minimally, and has lower risk to cause damage

AFM Vibration Modes & Challenges

Flexural Mode

- Cantilever vibrate vertically
- Vertical force measurement, topographic imaging

Torsional Mode

- Cantilever twists
- Friction force measurement, high-frequency measurement, phase imaging



Song & Bhushan, Appl. Phys. (99) 2006

Challenges

Slow response of cantilever requires long timeConventional probes can damage soft samples

Improving AFM Cantilever & Objectives

Faster Imaging

Ring-down Time (characteristic response time)

 $\tau = \frac{Q}{\pi f_0}$

Q: quality factor f_0 : resonant frequency

AFM in Liquid

Increased damping reduces Q



Not applicable to air environment

Small Cantilever

 Shorter cantilever increases f₀



Dufrêne et al., Nature Nanotech. (12) 2017

- Increases spring constant
 Optionally difficult to detect
- Optically difficult to detect

Softer Cantilever

Spring Constant

$$c = \frac{3EI}{L^3}$$

- E: Young's modulus
- I: cross-sectional moment of inertia
- L: cantilever's length

Micromachined Cantilever

- Low k and high f_0
- Increased force sensitivity



Hodges et al., Rev. Sci. Inst. (72) 2011

Increased Q

•Cantilever with high f_0 , low Q, and low k

Theory: Resonance Properties



 $\tau = \frac{Q}{\pi f_0}$

Ring-down time

Resonant frequency (f₀)



m : effective mass*k* : effective spring constantγ: damping coefficient



Hydrodynamic loading

$$\gamma = \frac{\pi^2}{2} \rho_f W^2 L f_0 \Gamma_{im}$$

 $Q\!\uparrow au\uparrow$

- *L*, *W*: length and width of cantilever
- ρ_f : density of fluid
- Γ : hydrodynamic function

Reducing Mass: Hollow Cantilever

Hollow Cantilever



Martinez et al., J. Micromech. Microeng. (26) 2016



Kim et al., Nano. Lett. (16) 2016

Patterned Cantilever









Nilsen et al., J. Micromech. Microeng. (29) 2019



Lin, Bargatin et al., Nat. Comms. 2018

Objectives

•Use these two approaches to improve AFM cantilevers

Fabrication Process



Fabricated Hollow Cantilever with Holes



Robustness



Preliminary Experimental Result (Flexural)



Theory: Hollow Beam Geometry

$$f_{0} = \frac{1}{2\pi} \sqrt{\frac{k}{m}}$$

$$k = \frac{3EI}{L^{3}}$$
E: Young's modulus of cantilever material *L*: moment of inertia (*I*)
Effective cantilever density (*p*)
Torsion Constant (*J*)
$$\frac{f_{0}}{WH} = \frac{1}{12} (H^{2} + W^{2})$$

$$\frac{WH}{W} = \frac{2W^{2}H^{2}t}{W + H}$$





*Equations used to derive these plots can be found in the supplementary slide at the end

• Hollow beam cantilevers with nanoscale walls have properties that depends on thickness (tunability)

Simulation: Hollow Cantilever with Holes

• Simulation results show f_0 and k varies with wall thickness and number of holes

Flexural Mode

Torsional Mode



Conclusion & Future Work

Conclusion

- High f_0 and low k in both flexural and torsional mode
- Tunability based on wall thickness and number of holes
- Potential benefits for dynamic biological samples



Future Work

- Viscous fluid damping simulation
- Torsional mode measurements



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Thank You.



Supplementary Slides

Theory: Hollow Beam Cantilever

| | Flexural | Torsional |
|---|---|--|
| Vacuum Resonant | $\frac{1.758}{\pi I^2} \int \frac{EI}{2}$ | $\frac{1}{AI} \left[\frac{GJ}{2} \right]$ |
| Trequency $f_{0(v)}$ | $\mu_{L^{-}} \sqrt{\rho_{c} A}$ | $\Gamma_{L} \sqrt{\rho_{c} r_{p}}$ |
| Damped Resonant Frequency $f_{0(f)}$ | $f_{0(\nu)} \sqrt{\frac{1}{1 + \left(\frac{\pi \rho_f W}{4 \rho_c H}\right) \Gamma_{re}}}$ | $\int_{\tau}^{T_{t(v)}} \sqrt{\frac{1}{1 + \left(\frac{\pi \rho_f b^4}{8 \rho_c I_p}\right) \Gamma_{re}}}$ |
| Quality Factor Q _f | $\frac{\frac{4\rho_{c}H}{\pi\rho_{f}W}+\Gamma_{re}}{\Gamma_{im}}$ | $\frac{\frac{8\rho_c I_p}{\pi\rho_f b^4} + \Gamma_{re}}{\Gamma_{im}}$ |
| Spring Constant k | $ \left(\left(k_{bending} \right)^{-1} + \left(k_{shear} \right)^{-1} \right)^{-1} $ $ = \left(\frac{1}{\left[\frac{H^3 E t}{2L^3} \left(1 + 3\frac{W}{H} \right) \right]} + \frac{1}{\left[\frac{GA}{L} \right]} \right)^{-1} $ | GJ L |

• Thin-Walled Hollow Cantilever:

$$\begin{split} I &= \frac{(W+2t)(H+2t)^3}{12} - \frac{bh^3}{12} \approx \frac{1}{6}H^3t \left(1+3\frac{W}{H}\right) & (t \ll W, H) \\ \rho_c &\approx \frac{([(W+2t)(H+2t)-WH]\rho_{alumina})}{WHL} = \frac{(H+W)}{WHL}t\rho_{alumina} & (t \ll W, H) \\ A &= (W+2t)(H+2t) \approx WH & (t \ll W, H) \\ J &= \frac{4t[(W+t)(H+t)]^2}{2(W+H+2t)} = \frac{2t(W+t)^2(H+t)^2}{W+H+2t} \approx \frac{2W^2H^2t}{W+H} & (t \ll W, H) \\ I_p &\approx \frac{(W+2t)(H+2t)t(W+H+4t)}{3} & (t \ll W, H) \end{split}$$

Sader, J. App. Phys. (84) 1998; Green & Sader, J. App. Phys. (92) 2002; Green et al., Rev. Sci. Inst. (75) 2004

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